

| L Number | Hits | Search Text | DB | Time stamp |
|-------------|------|---|---|---------------------|
| 1 | 9176 | 324/754-765.ccls. | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/11/06 15:30 |
| 2 | 13 | 324/754-765.ccls. and (interconnect adj2 (impedance or resistance)) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/11/06 16:11 |
| 3 | 195 | 324/754-765.ccls. and (substrate with socket) | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/11/06 16:12 |
| 4 | 94 | (324/754-765.ccls. and (substrate with socket)) and probe | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/11/06 16:21 |
| 5 | 474 | 324/754-765.ccls. and (probe same tester) and substrate | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/11/06 16:22 |
| 6 | 110 | (324/754-765.ccls. and (probe same tester) and substrate) and socket | USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB | 2003/11/06 16:22 |